

<b>Notice of References Cited</b>	Application/Control No. 09/802,165	Applicant(s)/Patent Under Reexamination CHUN ET AL.	
	Examiner Khawar Iqbal	Art Unit 2686	Page 1 of 1

**U.S. PATENT DOCUMENTS**

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
	A	US-2003/0072382	04-2003	Raleigh et al.	375/267
	B	US-6,597,678	07-2003	Kuwahara et al.	370/342
	C	US-6,101,399	08-2000	Raleigh et al.	455/561
	D	US-2003/0050016	03-2003	Boros et al.	455/67.4
	E	US-6,600,776	07-2003	Alamouti et al.	375/147
	F	US-6,590,532	07-2003	Ogawa et al.	342/378
	G	US-6,650,911	11-2003	Kang et al.	455/442
	H	US-6,463,303	10-2002	Zhao, Aiguo	455/562.1
	I	US-6,411,257	06-2002	Sorelius et al.	342/378
	J	US-6,373,433	04-2002	Espax et al.	342/368
	K	US-6,240,098	05-2001	Thibault et al.	370/431
	L	US-6,192,256	02-2001	Whinnett, Nicholas	455/562.1
	M	US-6,421,007	07-2002	Owen et al.	342/417

**FOREIGN PATENT DOCUMENTS**

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	N					
	O					
	P					
	Q					
	R					
	S					
	T					

**NON-PATENT DOCUMENTS**

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
	U	
	V	
	W	
	X	

\*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)  
Dates in MM-YYYY format are publication dates. Classifications may be US or foreign.